MOSFET - SiC Power, Single N-Channel, D2PAK-7L 1200 V, 20 mΩ, 98 A

Features

- Typ. $R_{DS(on)} = 20 \text{ m}\Omega$
- Ultra Low Gate Charge (typ. $Q_{G(tot)} = 220 \text{ nC}$)
- Low Effective Output Capacitance (typ. C_{oss} = 258 pF)
- 100% Avalanche Tested
- Qualified According to AEC-Q101
- RoHS Compliant

Typical Applications

- · Automotive On Board Charger
- Automotive DC/DC Converter for EV/HEV

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage		V_{DSS}	1200	V	
Gate-to-Source Voltage			V_{GS}	-15/+25	V
	Recommended Operation Values of Gate-to-Source Voltage		V_{GSop}	-5/+20	V
Continuous Drain Current (Note 2)	Steady State	T _C = 25°C	I _D	98	Α
Power Dissipation (Note 2)			P _D	468	W
Continuous Drain Current (Notes 1, 2)	Steady State	T _A = 25°C	I _D	8.6	Α
Power Dissipation (Notes 1, 2)			P _D	3.7	W
Pulsed Drain Current (Note 3)	T _A = 25°C		I _{DM}	392	Α
Single Pulse Surge Drain Current Capa- bility	$T_A = 25^{\circ}\text{C}$, $t_p = 10 \ \mu\text{s}$, $R_G = 4.7 \ \Omega$		I _{DSC}	807	Α
Operating Junction and Storage Temperature Range		T _J , T _{stg}	–55 to +175	°C	
Source Current (Body Diode)			I _S	46	Α
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 23 A, L = 1 mH) (Note 4)			E _{AS}	264	mJ
Maximum Lead Temperature for Soldering (1/8" from case for 5 s)		TL	300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

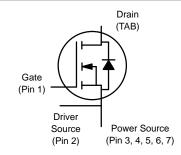
- 1. Surface mounted on a FR-4 board using1 in2 pad of 2 oz copper.
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 3. Repetitive rating, limited by max junction temperature.
- 4. EAS of 264 mJ is based on starting $T_J = 25^{\circ}\dot{C}$; L = 1 mH, $I_{AS} = 23$ A, $V_{DD} = 120$ V, $V_{GS} = 18$ V.



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
1200 V	28 mΩ @ 20 V	98 A



N-CHANNEL MOSFET



D2PAK-7L CASE 418BJ

MARKING DIAGRAM

AYWWZZ NVBG 020120SC1

A = Assembly Location

Y = Year WW = Work Week ZZ = Lot Traceability

NVBG020120SC1 = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping [†]
NVBG020N120SC1	D2PAK-7L	800 ea/ Tape&Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Case - Steady State (Note 2)		0.32	°C/W
Junction-to-Ambient - Steady State (Notes 1, 2)	$R_{ heta JA}$	41	

ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}$		1200			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J	I _D = 1 mA, referenced to 25°C			0.5		V/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$,	T _J = 25°C			100	μΑ
		V _{DS} = 1200 V	T _J = 175°C			1	mA
Gate-to-Source Leakage Current	I _{GSS}	$V_{GS} = +25/-15 \text{ V},$	V _{DS} = 0 V			±1	μΑ
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 20 mA	1.8	2.7	4.3	V
Recommended Gate Voltage	V_{GOP}			-5		+20	V
Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = 20 \text{ V}, I_D = 60 \text{ A}, T_J = 25^{\circ}\text{C}$			20	28	mΩ
		V _{GS} = 20 V, I _D = 60 A	A, T _J = 175°C		35	50	
Forward Transconductance	9FS	$V_{DS} = 20 \text{ V}, I_{D}$	= 60 A		34		S
CHARGES, CAPACITANCES & GATE RES	SISTANCE						
Input Capacitance	C _{ISS}	$V_{GS} = 0 \text{ V, f} = 1 \text{ MHz, V}_{DS} = 800 \text{ V}$			2943		pF
Output Capacitance	C _{OSS}				258		
Reverse Transfer Capacitance	C _{RSS}				24		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = -5/20 \text{ V}, V_{DS} = 600 \text{ V},$ $I_{D} = 80 \text{ A}$			220		nC
Threshold Gate Charge	Q _{G(TH)}				33		1
Gate-to-Source Charge	Q_GS				66		
Gate-to-Drain Charge	Q_{GD}				63		
Gate-Resistance	R_{G}	f = 1 MHz			1.6		Ω
SWITCHING CHARACTERISTICS, VGS =	10 V (Note 5)					-	<u> </u>
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = -5/20 \text{ V,}$ $V_{DS} = 800 \text{ V,}$ $I_{D} = 80 \text{ A,}$ $R_{G} = 2 \Omega$ inductive load			25	40	ns
Rise Time	t _r				41	66	
Turn-Off Delay Time	t _{d(OFF)}				46	74	
Fall Time	t _f				11	20	
Turn-On Switching Loss	E _{ON}				1670		μJ
Turn-Off Switching Loss	E _{OFF}				261		
Total Switching Loss	E _{tot}				1931		
DRAIN-SOURCE DIODE CHARACTERIST	гісѕ						
Continuous Drain–Source Diode Forward Current	I _{SD}	$V_{GS} = -5 \text{ V}, T_J = 25^{\circ}\text{C}$				46	А
Pulsed Drain–Source Diode Forward Current (Note 3)	I _{SDM}					392	
Forward Diode Voltage	V_{SD}	$V_{GS} = -5 \text{ V}, I_{SD} = 30$	A, T _J = 25°C		3.7		V
Reverse Recovery Time	t _{RR}	V _{GS} = -5/20 V, I _{SD} = 80 A, dI _S /dt = 1000 A/μs			31		ns
Reverse Recovery Charge	Q _{RR}				228		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Switching characteristics are independent of operating junction temperature

TYPICAL CHARACTERISTICS

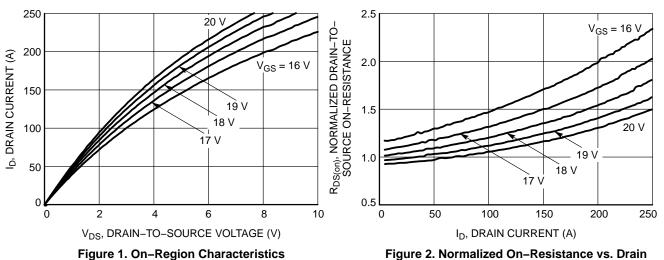


Figure 1. On-Region Characteristics

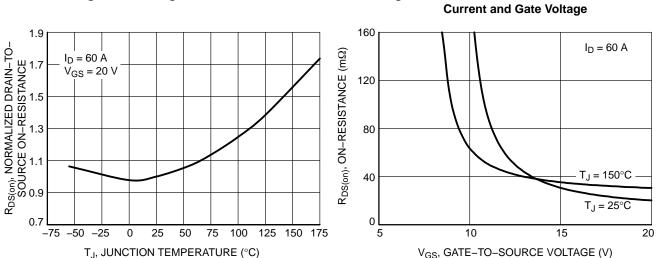


Figure 3. On-Resistance Variation with **Temperature**

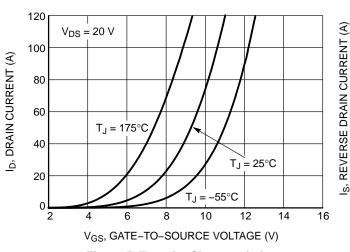
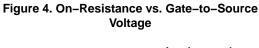


Figure 5. Transfer Characteristics



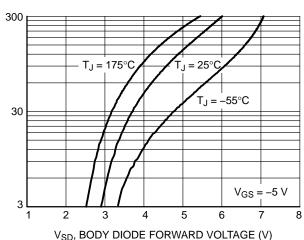


Figure 6. Diode Forward Voltage vs. Current

TYPICAL CHARACTERISTICS

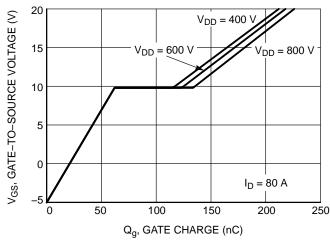


Figure 7. Gate-to-Source Voltage vs. Total Charge

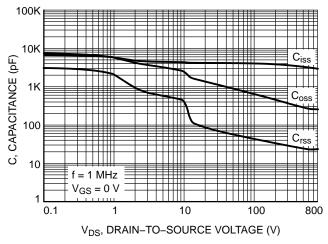


Figure 8. Capacitance vs. Drain-to-Source Voltage

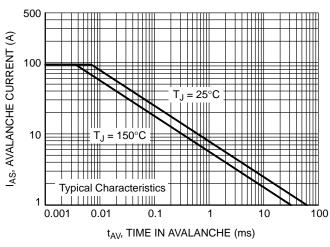


Figure 9. Unclamped Inductive Switching Capability

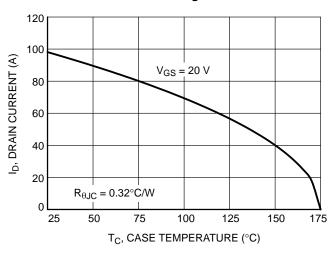


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

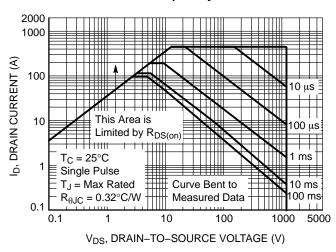


Figure 11. Maximum Rated Forward Biased Safe Operating Area

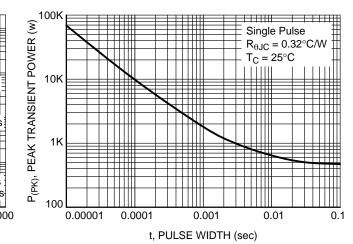


Figure 12. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS

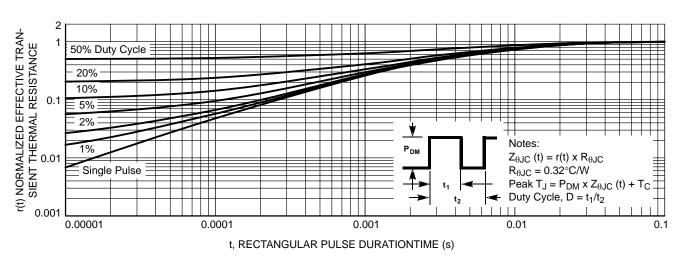
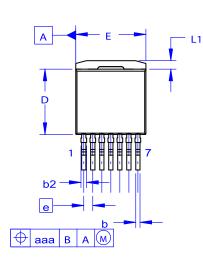
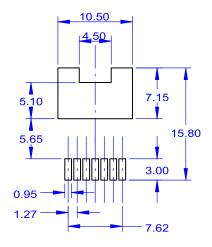


Figure 13. Junction-to-Case Transient Thermal Response Curve

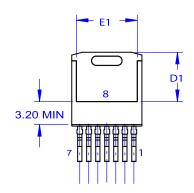
PACKAGE DIMENSIONS

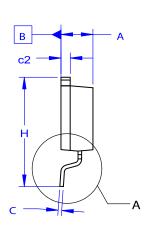
D²PAK7 (TO-263-7L HV) CASE 418BJ ISSUE A





LAND PATTERN RECOMMENDATION





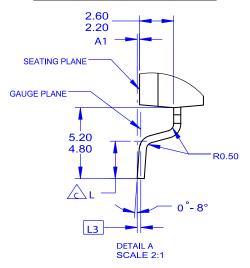
NOTES:

- A. PACKAGE CONFORMS TO JEDEC TO-263 VARIATION CB EXCEPT WHERE NOTED. B. ALL DIMENSIONS ARE IN MILLIMETERS.
- OUT OF JEDEC STANDARD VALUE.

 D. DIMENSION AND TOLERANCE AS PER ASME Y14.5-2009.

 E. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS.

DIM	MILLIMETERS				
DIIVI	MIN	NOM	MAX		
Α	4.30	4.50	4.70		
A 1	0.00	0.10	0.20		
b2	0.60	0.70	0.80		
b	0.51	0.60	0.70		
С	0.40	0.50	0.60		
c2	1.20	1.30	1.40		
D	9.00	9.20	9.40		
D1	6.75	6.95	7.15		
E	9.70	9.90	10.20		
E1	7.70	7.90	8.10		
е	~	1.27	?		
Н	15.10	15.40	15.70		
L	2.44	2.64	2.84		
L1	1.00	1.20	1.40		
L3	~	0.25	~		
aaa	~	?	0.25		



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